Search Notes

| Application/Control No. | Applicant(s)/Patent under Reexamination | |
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| 10/715,576 | SASSER ET AL. | |
| Examiner | Art Unit | |
| James D. Stein | 2874 | |

| SEARCHED | | | | | |
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| Class | Subclass | Date | Examiner | | |
| 385 | 88,92,76 | 3/22/2006 | JDS | | |
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| SEARCH NOTES (INCLUDING SEARCH STRATEGY) | | | | |
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| | DATE | EXMR | | |
| See attached EAST search history | 3/22/2006 | JDS | | |
| IEEE and INSPEC | 3/21/2006 | JDS | | |
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